

RELIABILITY TEST REPORT

Report No: < K200304016>

Log-in Date : 2020/02/25 Report Date : 2020/03/03

Prepared by :

Richard Kuo

Richard Kuo

Engineer,

Reliability Analysis Division +886-3-6116678 ext. 6568

rasys@ma-tek.com

Reviewed by:

Rex Chung

Rex Chung

Manager,

Reliability Analysis Division

+886-3-6116678 ext. 6524

rexchung@ma-tek.com

Approved by:

Woody Chuang

Woody Chuang

Director,

Reliability Analysis Division

+886-3-6116678 ext. 6500

woodychuang@ma-tek.com

Disclaimer:

- 1. This report is proprietary to the client and may not be copied, reproduced or referred (whether in whole or in part) to any other party by any means without the prior written consent of MA-tek.
 - 本報告非經本公司事前書面同意,不得複製、轉載、提述(全部或部份內容)於他人。
- 2. The information contained in or referred to in this report is based solely on information, data and/or samples provided to MA-tek by the client. All of the contents of this report shall be treated as a whole. Any single page of this report shall not be used or interpreted separately.
 - 本報告僅針對客戶提供的試樣作出技術分析,報告中的任意頁次不可以被拆解來單獨使用。
- 3. This report shall be used as technical reference only. Unless with the prior written consent of MA-tek, this report shall not be used for any other purpose, especially in legal disputes, nor be evidenced as MA-tek's opinions for any specific case.
 - 本報告僅限於作技術參考,非經本公司事前書面之同意,此報告不得用於訴訟案件,亦不得做為本公司就具體個案表示意見之證明。



Page: 1 Date: 2020/03/03

Version: 01

MA-tek Milestone, Accreditation & Certificates

MA-tek is a company with ISO 9001, IECQ 17025 and ISO 27001 certifications and is the only lab in Taiwan awarded the Industrial Excellence Award by the IDB (2008). MA-tek's method of dimension measurement of analytical data can be traced back to the NIST Standard (National Institute of Standard and Technology).

- 2004 Certified by ISO 9001 and IECQ 17025.
- 2006 Elected as the Distinguished Enterprise by the Industry Development Bureau (IDB).
- 2006 Awarded #32 in the Taiwan Top 50 and #157 in the Asia Top 500 Fastest Growing Companies by Deloitte.
- 2008 Awarded the best performance company of Industrial Excellence Award by the Economy Ministry's Industry Development Bureau (IDB).
- 2009 Listed on the Taiwan OTC market (3587)
- 2012 Awarded #474 in the Asia Top 500 Fastest Growing Companies by Deloitte.
- 2013 A+ companies in Taiwan by Global Views Monthly Magazine.
- 2015 Certified by ISO 27001.







ISO/IEC 27001 IECQ 17025 ISO 9001

Page: 2 Date: 2020/03/03

Version: 01

MA-tek Core Team

■ CEO - Dr. Yong-Fen Hsieh



More than 20 years of experience in various fields of IC(Si), TFT-LCD, LED(III-V, II-VI), LCOS, GaAs, and Ge/ Metal contacts system.

Specialized in TEM analysis, fault isolation/failure analysis, analytical lab operation, quality management (QE, QA, QS, TQM), and materials-related fundamental research.

■ MA - Dr. J.C. Hu



More than 10 years of experience in various fields of Advanced IC exploratory & processing, LED, PV, industry, international technology collaboration, materials analysis.

Specialized in TEM, HRTEM, EDX, EELS, PFA and SEM related analysis, materials science, applied chemistry.

■ FA - Max Kuo



More than 10 years of experience in IC EFA (EMMI, OBIRCH, LCD, etc.) and PFA (Structure and Process diagnosis) analysis.

Specialized in fault isolation/failure analysis, SEM, chemical analysis, FA total solution consulting and coordination.

■ RA - Woody Chuang



More than 20 years of experience in PCB, CCL, FCCL, FPCB and Server ODM/OEM.

Specialized in PCB/FPCB related reliability test and failure analysis, server component reliability research and material analysis.

■ SA - Ming-Ching Huang



More than 10 years of experience in surface analysis of IC(Si), TFT-LCD, LED, LCOS, GaAs, and solar cells.

Specialized in SIMS, Auger, ESCA/XPS, Scanning Capacitance Microscopy, Atomic Force Microscopy, Magnetic Field Microscopy, and SRP.

Page: 3 Date: 2020/03/03



Version: 01

Contents

1	Bacl	Background Information			
	1.1	Client Inf	formation	5	
	1.2	Testing I	nquiry	5	
	1.3	Pass/Fai	l Criteria	5	
2	Test	ing Sumn	nary	6	
3	Test	ing Items	, Conditions, and Raw Data	7	
	3.1	Surface	Insulation Resistance Test	7	
		3.1.1	Test System	7	
		3.1.2	Test Method and Condition		
		3.1.3	Test Results	8	
		314	Pictures of Surface Insulation Resistance Test	q	



Version: 01

1 Background Information

1.1 Client Information

TOCALO & HAN TAI TW CO., LTD

User Name: Lily Lin

TEL: +886-3-758-0791 Ext.1075

1.2 Testing Inquiry

Model Name	Test Item	Quantity
20200221-A		
20200221-В	Surface Insulation Resistance Test	3 pcs
20200221-C		

1.3 Pass/Fail Criteria

N/A



Page: 5 Date: 2020/03/03



Materials Analysis Technology Inc. 4F, No.1, Jinshan 7th St., Hsinchu City, Taiwan 300, R.O.C.

Report No.: K200304016

Version: 01

Testing Summary

Test Item	Condition	Model Name	Judgment
	Test Voltage: 10 V	20200221-A	N/A
Surface Insulation	Current Range : 500 uA	20200221 /\ 20200221-B	
Resistance Test	Thickness: 10 um		
	Test Time: 60 Sec	20200221-C	



Version: 01

Testing Items, Conditions, and Raw Data 3

3.1 **Surface Insulation Resistance Test**

3.1.1 Test System

Brand/Model No.	Calibration Date
Agilent / 4339B	2018/11/23~2020/05/23

3.1.2 Test Method and Condition

Specification: The test based on Customer's specification.

Environmental Temperature and Humidity: 25°C±5°C / 55%R.H±10%

Test Condition:

Test	Condition	
	Test Voltage	10 V
Surface Insulation Resistance Test	Current Range	500 uA
	Thickness	10 um
	Test Time	60 Sec



Report No.: K200304016 Version: 01

3.1.3 Test Results

Test Result below to table:

Electrical verification will be conducted by client.

Sample name	Vout	Clmt	Rs
20200221-A	10.00 V	500.0 uA	+3.0903E+11 Ω
20200221-B	Overcurrent		
20200221-C	10.00 V	500.0 uA	+2.9813E+14 Ω
Test Posults/20200221_A)		Toet Posulte/	20200221-C)





Page: 8 Date: 2020/03/03

Version: 01

3.1.4 Pictures of Surface Insulation Resistance Test



Proprietary, DO NOT COPY WITHOUT PERMISSIONThe content of this report is ONLY valid to the case of corresponding report number. Any page, or pages, of this report can not be used separately.

Page: 9 Date: 2020/03/03



Report No.: K200304016 Version: 01

Page: 10

Date: 2020/03/03

